510 Validation

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Tracking Meeting

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510 Validation

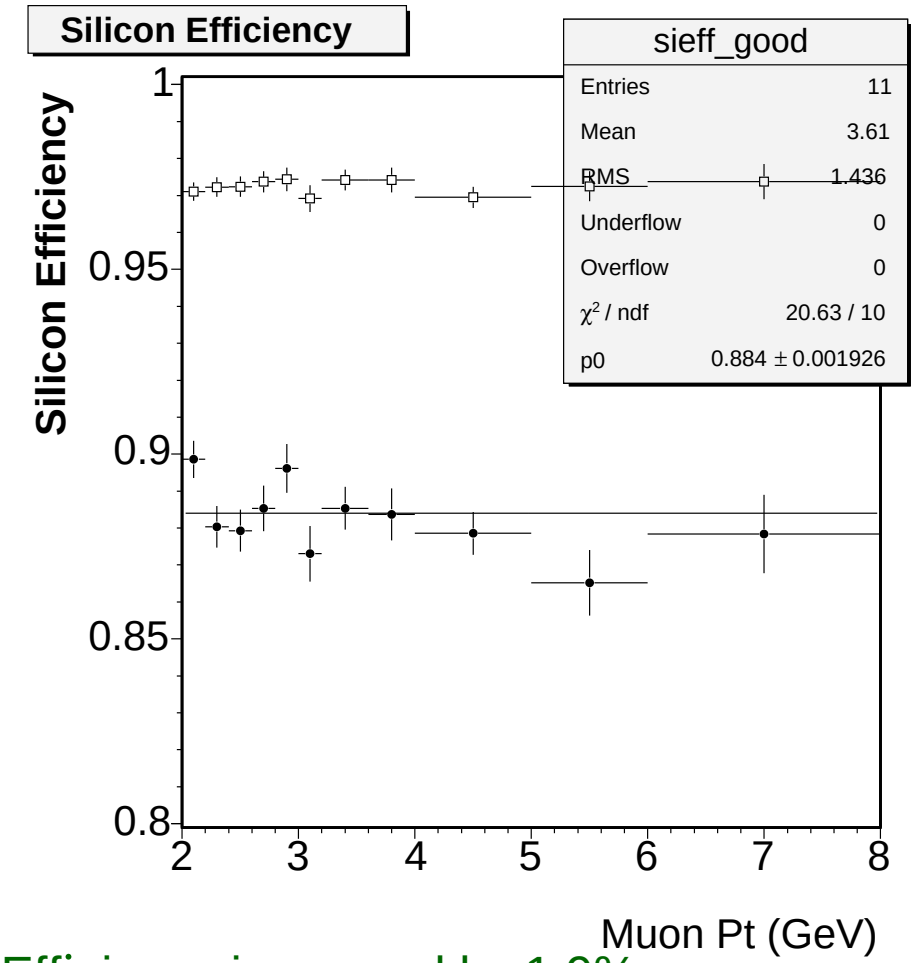
Data Set

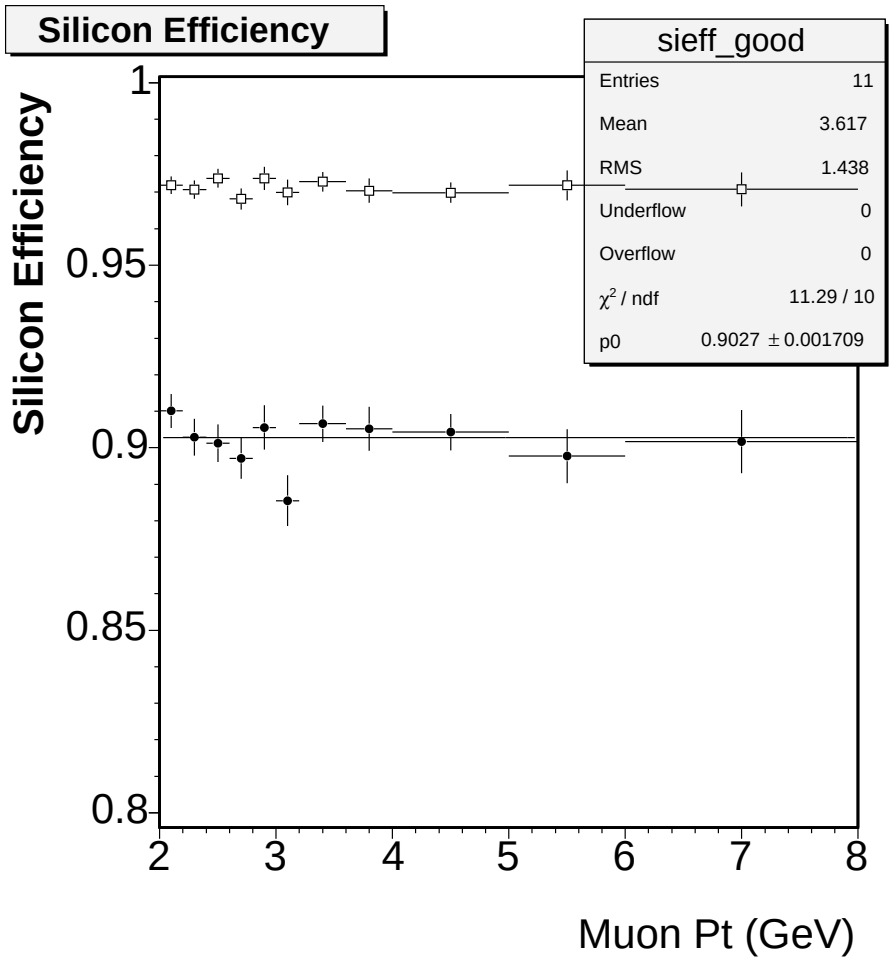
- Post shutdown J/ψ data
- Trigger confirmed J/ψ

Studies

- Background subtracted efficiency
- Background subtracted fake rate
  - % signed impact parameter beyond -150um(3 sigma)
- COT and silicon mass width
- d0 width and d0 vs phi

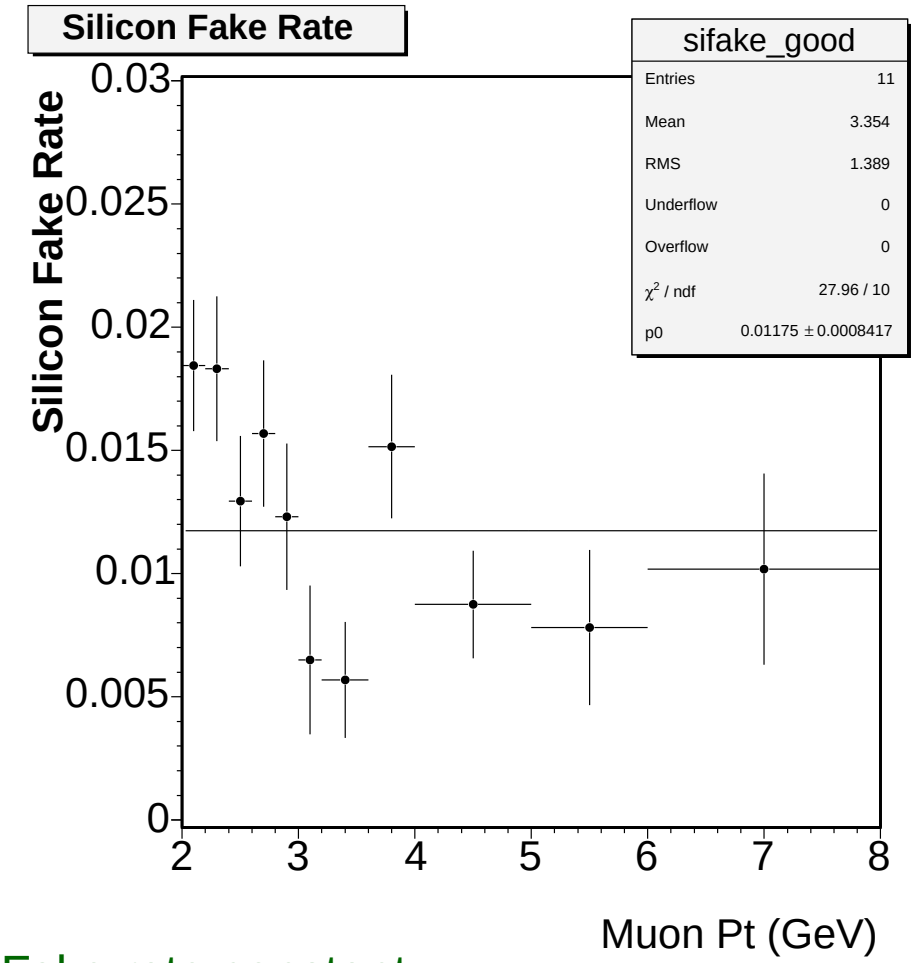
Silicon Efficiency

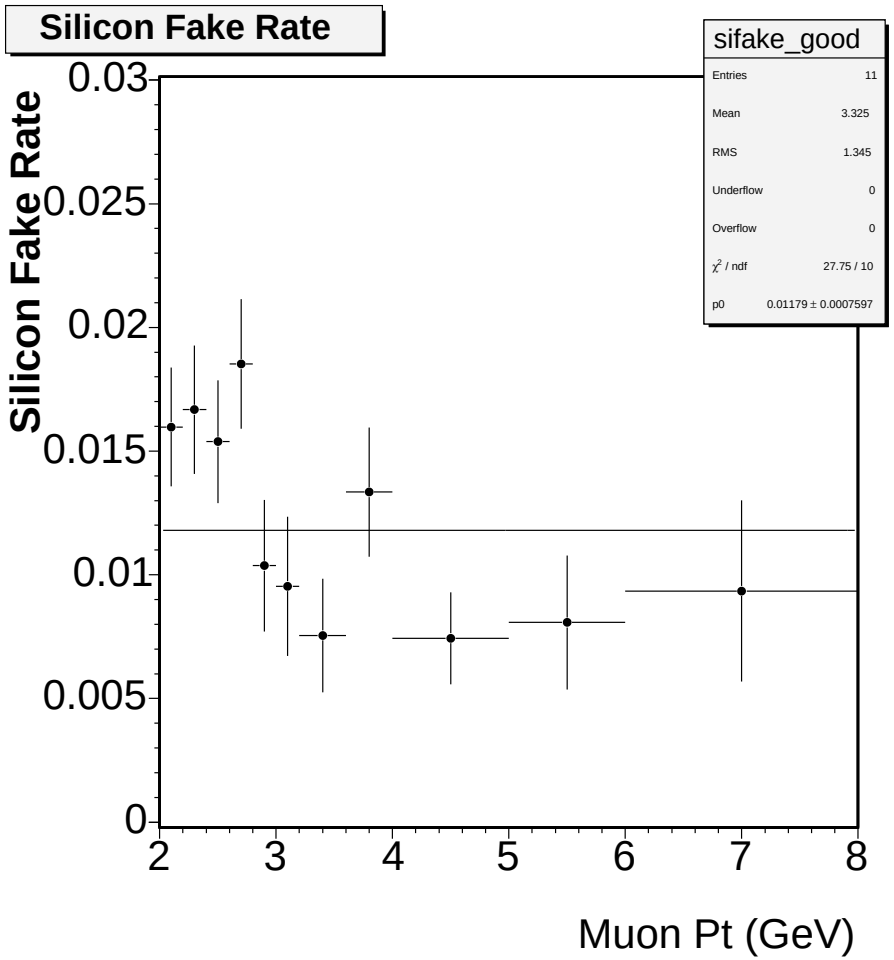




Efficiency increased by 1.9%

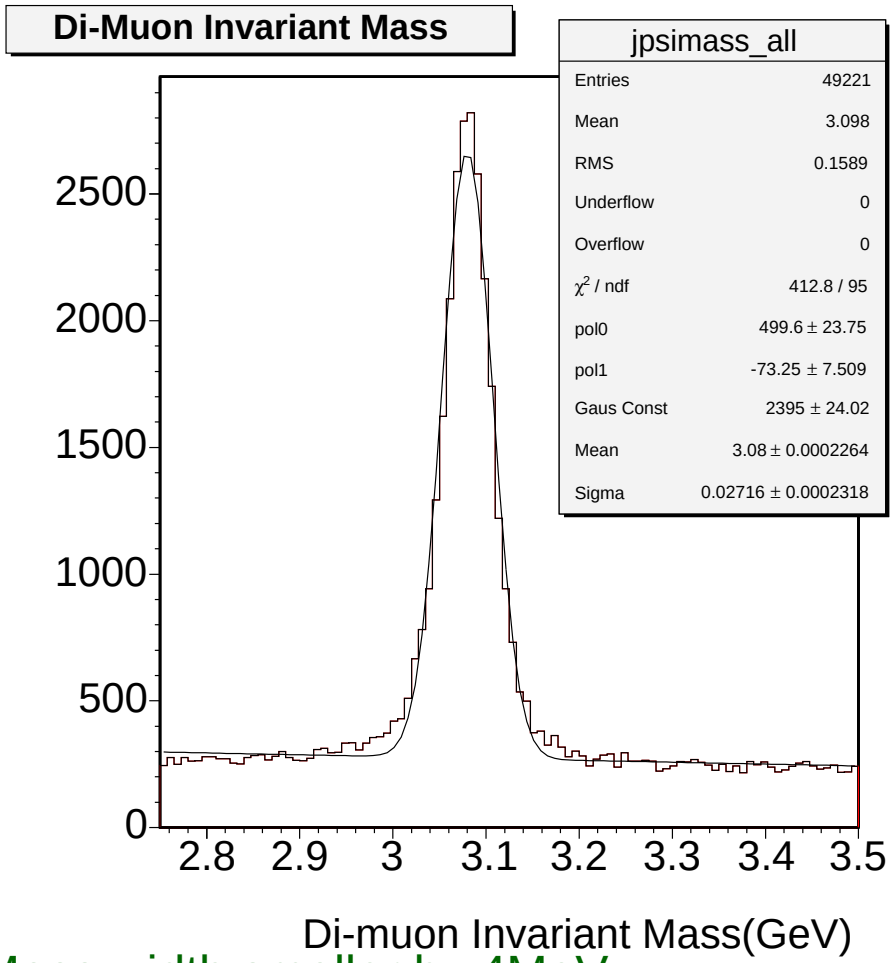
Silicon Fake Rate

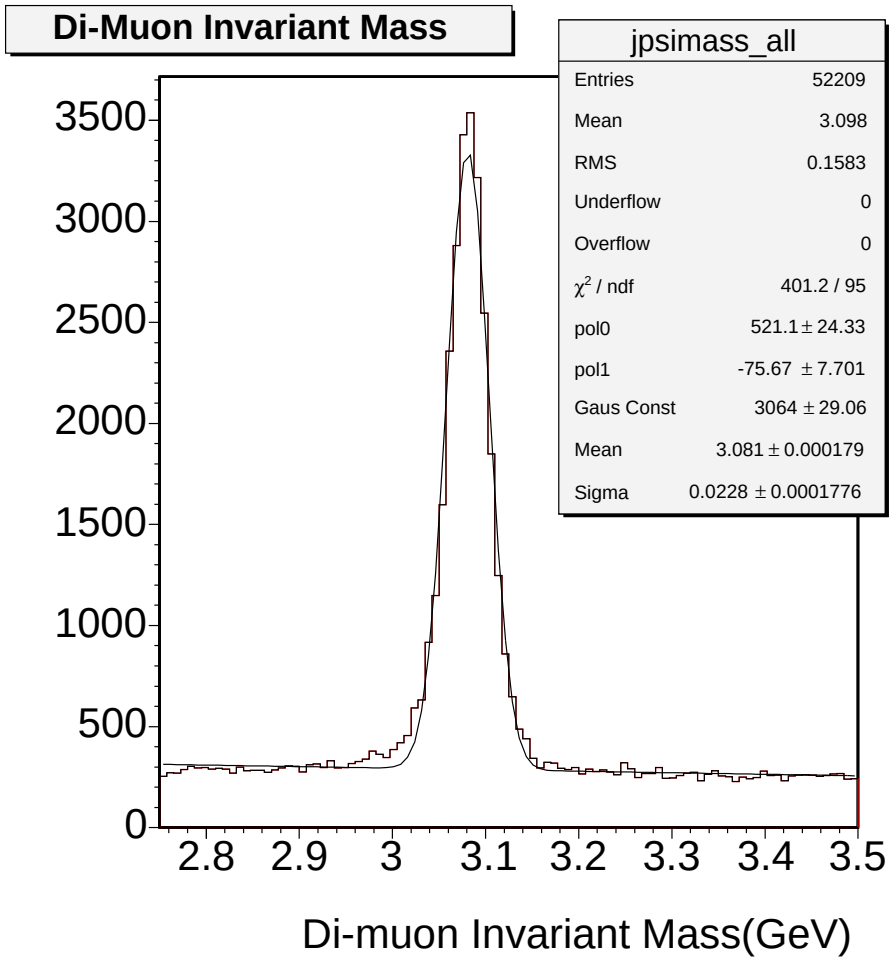




Fake rate constant

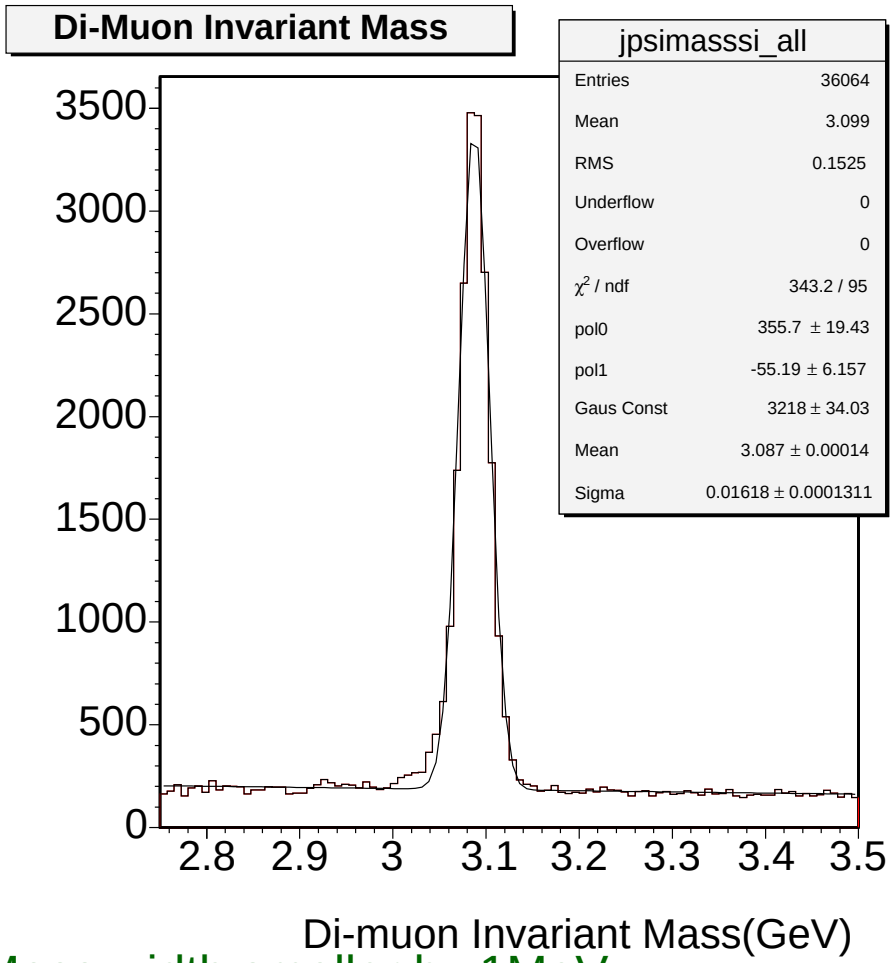
Cot Mass Width

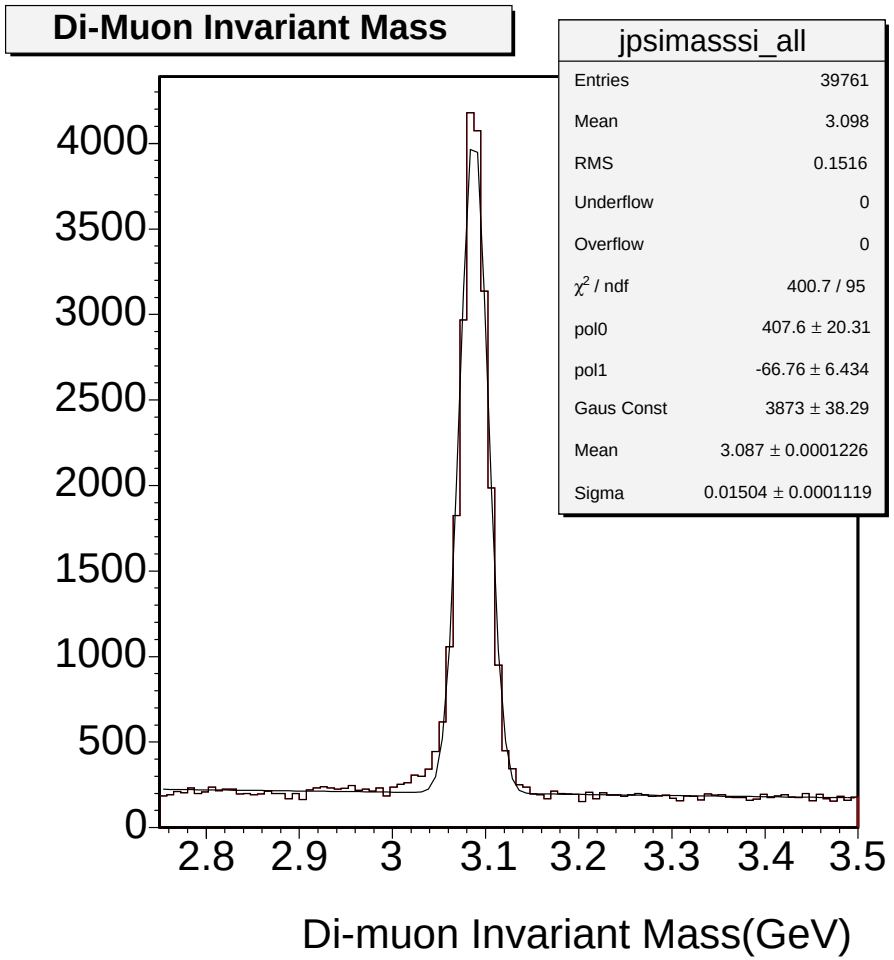




Mass width smaller by 4MeV

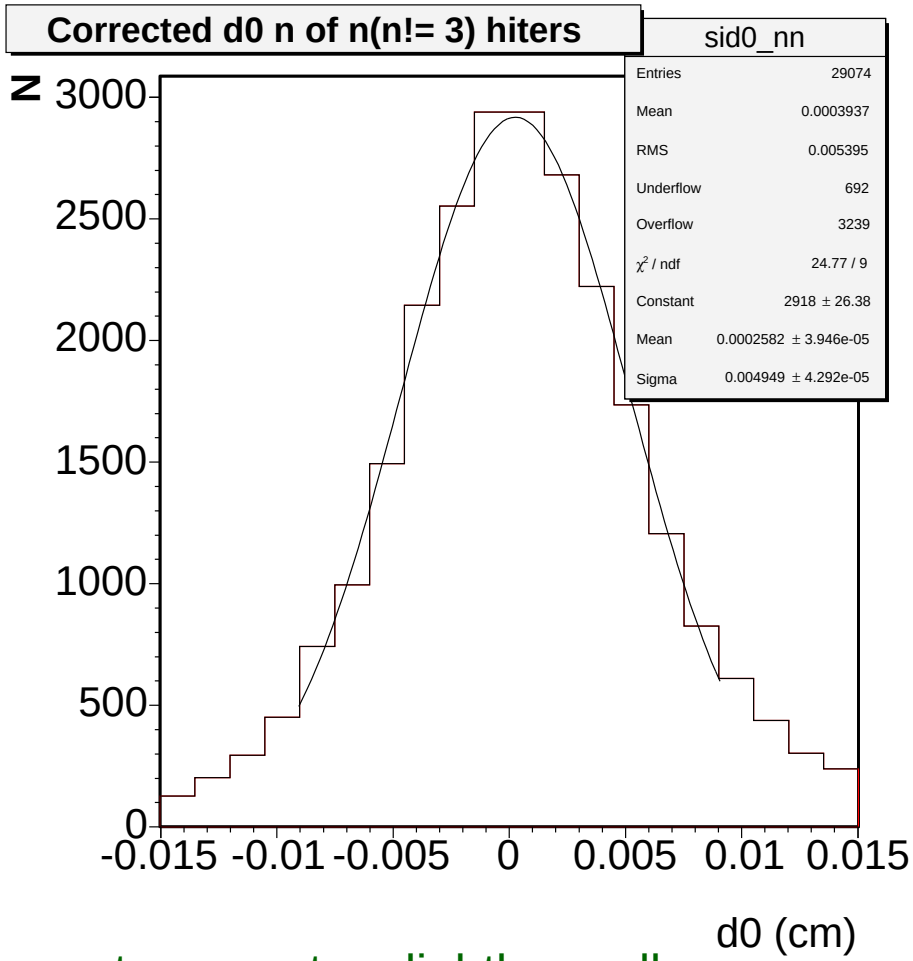
Silicon Mass Width

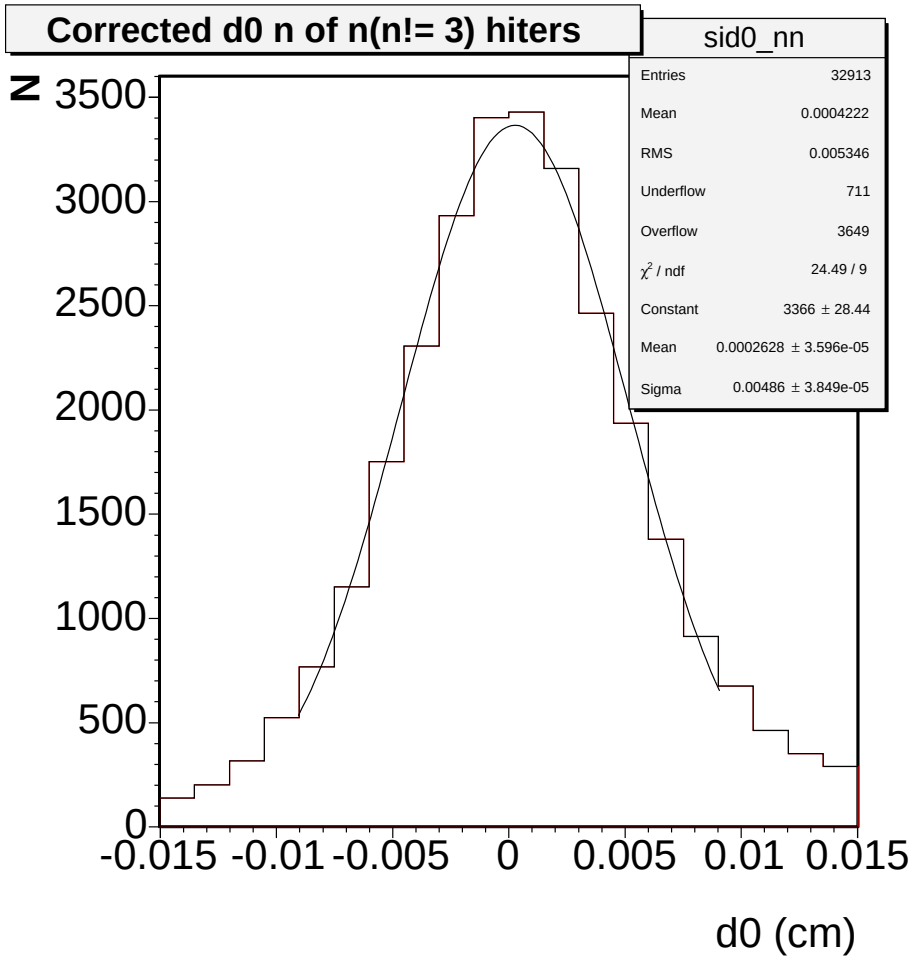




Mass width smaller by 1MeV

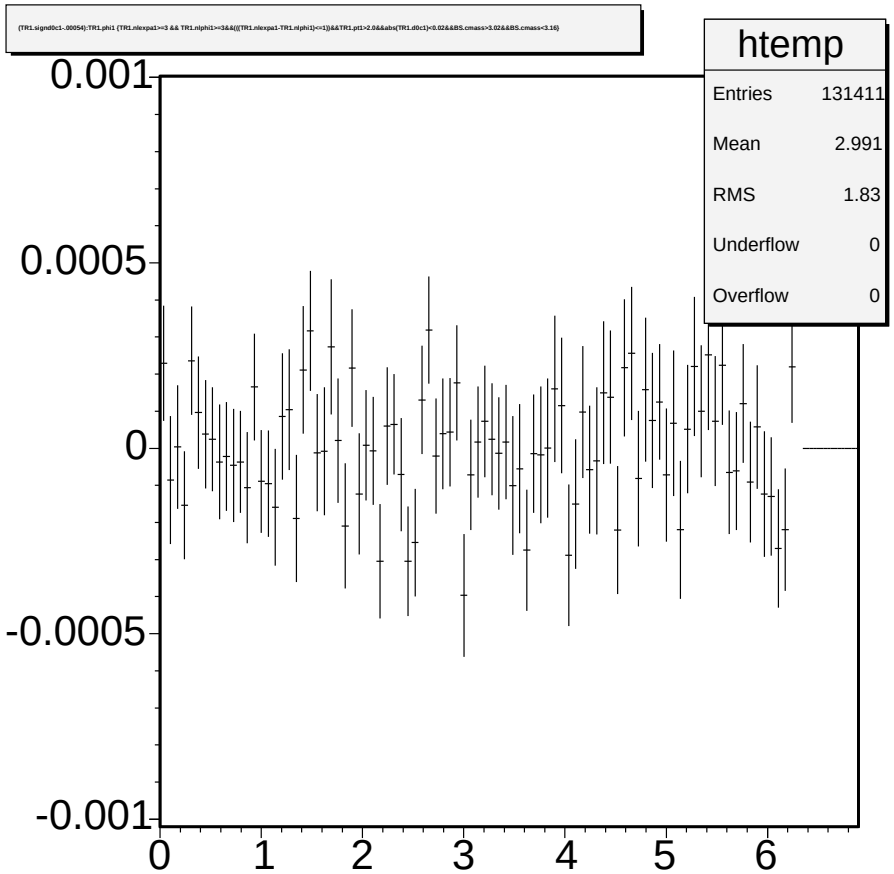
Impact Parameter Width

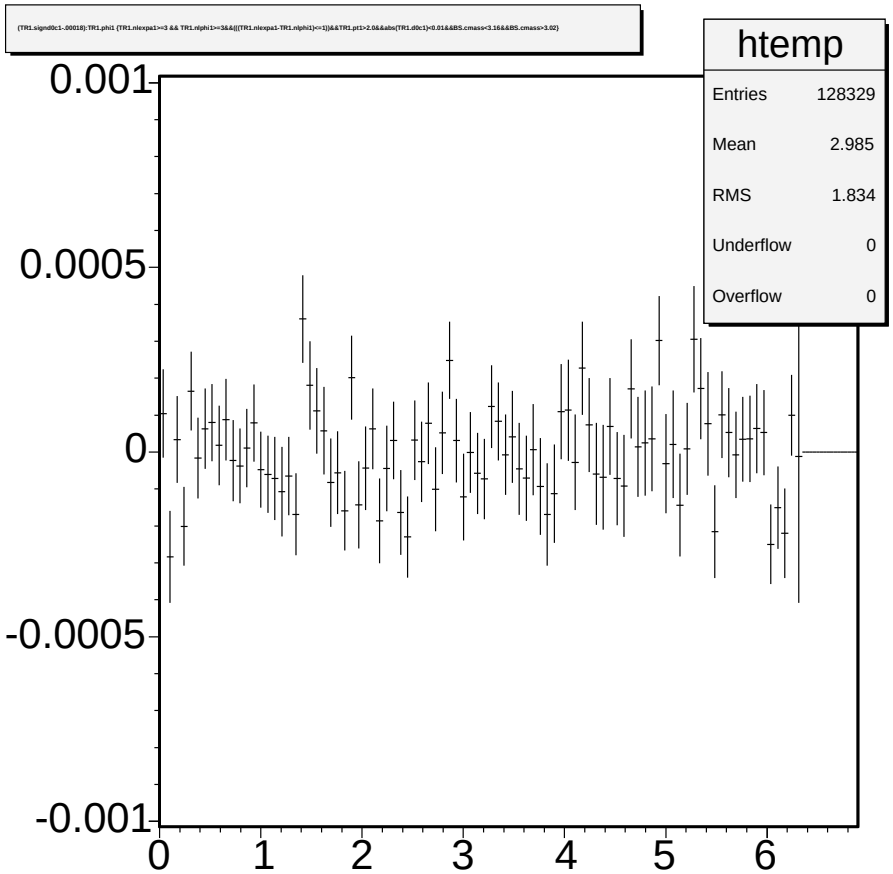




Impact parameter slightly smaller

Impact Parameter vs. Phi





Clearly improved